

ELASTIC CHARACTERISTICS OF THE  
INTERFACE 'INCLUSIONS OF Te - MATRIX'  
IN CdTe, HgTe AND CdHgTe CRYSTALS AND  
HETEROSTRUCTURES ON THEIR BASIS

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S u m m a r y

The characteristics of the interface 'matrix - Te inclusions' in crystals CdTe, HgTe and CdHgTe and heterostructures on their basis are estimated: the density energy of the inclusion-matrix interface; spacing between misfit dislocations; critical thickness for coherence loss in the matrix; elastic strain in the inclusion-matrix system; strains in the system caused by a difference of the lattice parameters and thermal expansion coefficients; and length of cracks in the matrix. Values of stresses caused by a difference of lattice parameters are close to values of stress tensor components around inclusions which are estimated on the basis of the Mott - Nabarro model.